At NTT-AT, we can provide a variety of product inspection data to match whatever you need.

- Film thickness distribution
- Composition distribution
- Sheet resistivity distribution
- Mobility distribution
- AFM
- Wafer shape (SORI)
- Surface analysis (Particle inspection)
- XRD fitting
- C-V carrier density profile
...and others

AFM observation

Sheet resistivity distribution measurement example

C-V carrier density profile evaluation example

Surface analysis evaluation example

※ The contents of this catalogue may be changed without previous notification.

For more information:

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